

Electronic Information Disclosure Statement

METHOD AND DESIGN FOR MEASURING SRAM ARRAY LEAKAGE MACRO (ALM)

JC474 U.S. PTO
10/064302
07/01/02

Application:

Confirmation:

Applicant(s): Matthew Breitwisch

Docket Number: BUR920010139

Group Art Unit:



Examiner:

search string: (4685086 or 4860261 or 5132929 or 5659511 or 5732015 or 5936902 or 6259623).pn.

■ *That no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the statement after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 1.56(c) more than three months prior to the filing of the information disclosure statement.*

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Citation No.	Patent Number	Date	Bar Code	Patentee	Class	Subclass
<input checked="" type="checkbox"/>	P01	4685086	1987-08-04		Tran		
<input checked="" type="checkbox"/>	P02	4860261	1989-08-22		Kreifels et al.		

<i>[initials]</i>	P03	5132929	1992-07-21	<i>[barcode]</i>	Ochii
<i>[initials]</i>	P04	5659511	1997-08-19	<i>[barcode]</i>	Huang
<i>[initials]</i>	P05	5732015	1998-03-24	<i>[barcode]</i>	Kazerounian et al.
<i>[initials]</i>	P06	5936902	1999-08-10	<i>[barcode]</i>	Hsu et al.
<i>[initials]</i>	P07	6259623	2001-07-10	<i>[barcode]</i>	Takahashi

Remarks

(Remarks are not for responding to an office action.)

JP7312097A - 11/28/95 - Japan (Abstract) "SRAM Leakage Current Reduction Method", Research Disclosure, December 2000, pp. 2237-2239, Disclosed by International Business Machines Corporation

Signature

Examiner Name	Date
<i>Ene Arduong</i>	4/03